Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/574,939	MIYAI ET AL.
Examiner	Art Unit
Danny Worrell	3765

	SFAR	CHED	
Class	Subclass	Date	Examiner
66	125R		
	126R		
	127		
	128		
	129	1/7/2007	LDW

INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
		, 	
	 		

·	(INCLUDING SEARCH STRATEGY) DATE EXM		
		 	
		,	
		}	
		-	